

2N1870A-2N1874A

High-reliability discrete products and engineering services since 1977

SILICON CONTROLLED RECTFIERS

FEATURES

- Available as "HR" (high reliability) screened per MIL-PRF-19500, JANTX level. Add "HR" suffix to base part number.
- Available as non-RoHS (Sn/Pb plating), standard, and as RoHS by adding "-PBF" suffix.

MAXIMUM RATINGS							
Ratings	Symbol	2N1870A	2N1871A	2N1872A	2N1873A	2N1874A	Unit
Repetitive peak off state voltage	V _{DRM}	30	60	100	150	200	v
Repetitive peak reverse voltage	V _{RRM}	30	60	100	150	200	v
DC on state current							
100°C ambient	Ι _Τ			250			mA
100°C case				1.25			А
Repetitive peak on state current	I _{TRM}	Up to 30				А	
Peak one cycle surge (non-repetitive) on state current	I _{TSM}			15			А
Peak gate current	I _{GM}	250					mA
Average gate current	I _{G(AV)}			25			mA
Reverse gate voltage	V _{GR}			5			V
Thermal resistance, junction to case	R _{ejc}			20			°C/W
Operating and storage temperature range	T _J , T _{stg}			-65 to 150			°C

ELECTRICAL CHARACTERISTICS (T_A = 25°C unless otherwise specified)

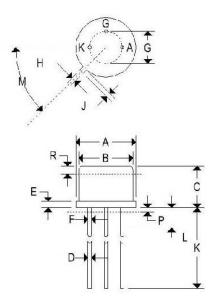
Test	Symbol	Min.	Тур.	Max.	Units	Test Conditions
25°C tests	·					
Off-state current	I _{DRM}	-	0.5	10	μΑ	$R_{GK} = 1K$, $V_{DRM} = +rating$
Reverse current	I _{RRM}	-	0.5	10	μΑ	$R_{GK} = 1K$, $V_{RRM} = -$ rating
Gate trigger voltage	V _{GT}	0.4	0.55	0.8	V	R_{GS} = 100ohms, V_D = 5V
Gate trigger current	I _{GT}	-	30	200	μA	R_{GS} > 10K ohms, V_D = 5V
On-state voltage	V _{TM}	-	1.8	2.5	V	I _{TM} = 2A (pulse test)
Off-state voltage – critical rate of rise	dv _c /dt	100	-	-	V/µs	Specified test circuit
Reverse gate current	I _{GR}	-	0.5	10	μA	V_{GRM} = 5V, anode open
Holding current	I _H	0.3	-	5.0	mA	$I_{G} = -150 \mu A, V_{D} = 5V$
125°C tests	·					
High temperature off state current	I _{DRM}	-	15	100	μΑ	$R_{GK} = 1K$, $V_{DRM} = + rating$
High temperature reverse current	I _{RRM}	-	15	100	μΑ	$R_{GK} = 1K$, $V_{RRM} = -$ rating
High temperature gate non-trigger voltage	V _{GD}	0.2	-	-	V	R_{GS} = 100 ohms, V_D = 5V
High temperature holding current	I _H	0.2	-	-	mA	$I_{G} = -150 \mu A, V_{D} = 5V$
-65 °C tests	·	. <u> </u>	•			
Low temperature gate trigger voltage	V _{GT}	-	-	1.0	V	$R_{GK} = 100 \text{ ohms}, V_D = 5V$
Low temperature gate trigger current	I _{GT}	-	-	500	μΑ	R_{GK} > 10K ohms, V_D = 5V
Low temperature holding current	I _H	-	-	15	mA	$I_{G} = -150 \mu A$, $V_{D} = 5V$

Voltage ratings apply over the full operating temperature range provided the gate is connected to the cathode through a resistor, 1K or smaller, or other adequate gate bias is used.



MECHANICAL CHARACTERISTICS

Case:	ТО-9
Marking:	Body painted, alpha-numeric
Pin out:	See below



	TO-9						
	Inc	hes	Millimeters				
	Min	Max	Min	Max			
A	0.275	0.335	6.990	7.750			
В	0.290	0.370	7.370	9.400			
С	0.200	0.260	5.080	6.600			
D	1.500	-	38.100	(23)			
E	0.010	0.030	0.254	0.762			
F	0.015	0.018	0.381	0.457			
G	0.200 TYP		5.080 TYP				
Н	0.100 TYP		2.540 TYP				
J	0.100 TYP		2.540 TYP				

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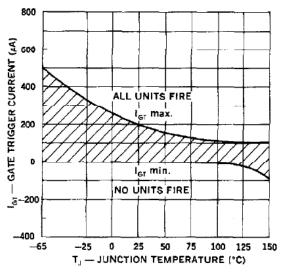
SILICON CONTROLLED RECTFIERS



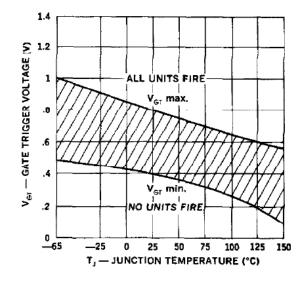
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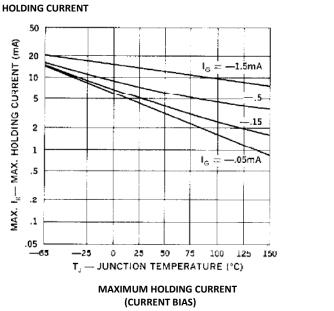


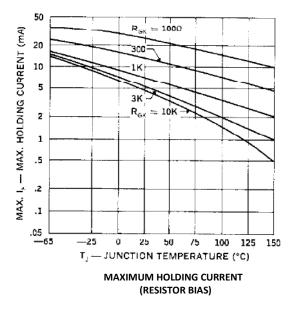






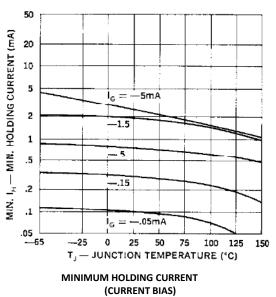
GATE TRIGGER VOLTAGE





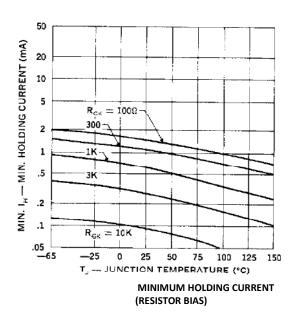


HOLDING CURRENT

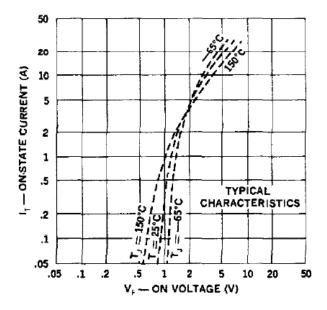


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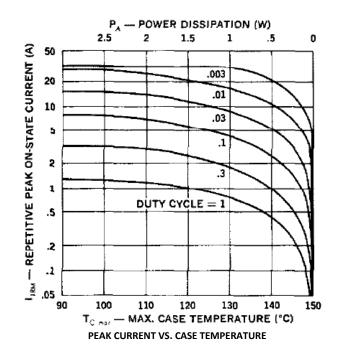
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CURRENT RATINGS – THERMAL DESIGN

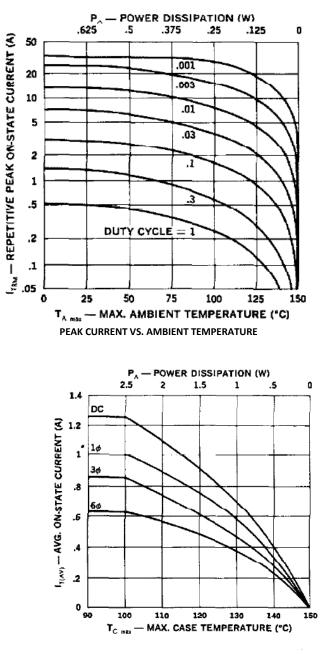


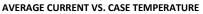
ON-STATE CURRENT VS VOLTAGE





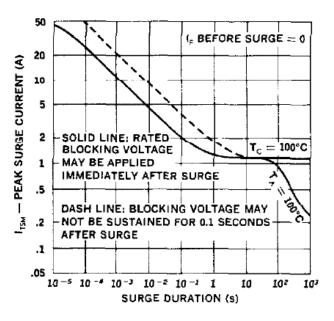
CURRENT RATINGS – THERMAL DESIGN



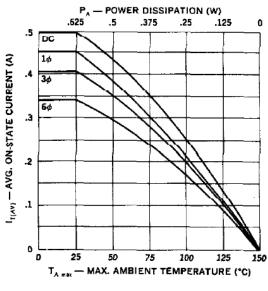


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SILICON CONTROLLED RECTFIERS



SURGE CURRENT VS. TIME



AVERAGE CURRENT VS. AMBIENT TEMPERATURE